

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 116381		APPLICATION NO. 10/626,548	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Yohei MAEKAWA			
				FILING DATE July 25, 2003		GROUP 2157 2155	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
<i>nm</i>	1	US 2002/0093675 A1	07/18/2002	MATSUDA	—	—	
<i>nm</i>	2	US 2002/0161740 A1	10/31/2002	NAKAMURA et al.	—	—	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
<i>nm</i>	3	JP A 2002-23983 w/abstr. & trans.	01/25/2002	JAPAN	—	—	
<i>nm</i>	4	JP A 11-161441 w/abstr. & trans.	06/18/1999	JAPAN	—	—	
<i>nm</i>	5	JP A 2000-347826 w/abstr. & trans.	12/15/2000	JAPAN	—	—	
<i>nm</i>	6	JP A 2002-218153 w/abstr. & trans.	08/02/2002	JAPAN	—	—	
<i>nm</i>	7	JP A 09-149061 w/abstr. & trans.	06/06/1997	JAPAN	—	—	
<i>nm</i>	8	JP A 2001-175626 w/abstr. & trans.	06/29/2001	JAPAN	—	—	
<i>nm</i>	9	JP A 11-203087 w/abstr. & trans.	07/30/1999	JAPAN	—	—	
<i>nm</i>	10	EP 0 930 748 A2	07/21/1999	EUROPE	—	—	
<i>nm</i>	11	JP A 2002-86859 w/abstr. & trans.	03/26/2002	JAPAN	—	—	
<i>nm</i>	12	WO 01/73558 A1 w/ abstract	10/04/2001	WIPO	—	—	
<i>nm</i>	13	EP 1 191 450 A1	03/27/2002	EUROPE	—	—	
<i>nm</i>	14	JP A 11-249839 w/abstr. & trans.	09/17/1999	JAPAN	—	—	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER <i>liten w2</i>				DATE CONSIDERED 7/13/07			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: September 8, 2005

Sheet 1 of 1

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>mm</i>	1	EP 0 930 748 A2	07/21/1999	Europe	—	—
<i>mm</i>	2	JP A 11-203087 (with abstract and translation)	07/30/1999	Japan	—	—
<i>mm</i>	3	JP A 8-249281 (with abstract and translation)	09/27/1996	Japan	—	—
<i>mm</i>	4	JP A 11-249839 (with abstract and translation)	09/17/1999	Japan	—	—
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
EXAMINER	<i>Leila W</i>			DATE CONSIDERED <i>7/13/07</i>		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Date: May 10, 2004